



FOR IMMEDIATE RELEASE

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**AEHR TEST SYSTEMS RECEIVES FOLLOW-ON ORDER FOR ITS FOX-15™
WAFER-LEVEL BURN-IN AND TEST SYSTEM FROM MICRONAS**

Fremont, CA (September 15, 2009) – Aehr Test Systems, a leading supplier of semiconductor test and burn-in equipment, today announced it has received a follow-on order of more than \$1 million for its FOX-15 wafer-level burn-in and test system from Micronas, a leading supplier of automotive and industrial integrated circuits. Aehr Test expects to ship the system by the end of calendar 2009.

Wilfried Lowinski, Vice President Operations Backend at Micronas, commented, “We have selected the FOX-15 wafer level burn-in system because it significantly reduces our production burn-in costs compared to package burn-in and allows us to deliver a highly reliable product to our automotive customers at a competitive price. Doing burn-in at the wafer level, before the die are packaged, also allows us to collect reliability data much earlier in our production process so that we can monitor and continuously improve our wafer fabrication process and yields. We are pleased with the close cooperation between the team at Aehr Test and our engineers in implementing this cutting-edge technology for burning-in Micronas’ state-of-the-art Hall sensors.”

“This strategic order is in a growing market area that could represent a significant revenue stream for our FOX systems,” said Rhea Posedel, chairman and chief executive officer of Aehr Test Systems. “The ability to cost-effectively probe a full wafer on a single touchdown allows us to meet the stringent quality demands of the automotive market. In addition, we believe the need for wafer-level test and burn-in will continue to grow as the increasing demand for multi-chip packages in automotive and mobile electronics products drives the need for known-good-die.”

As usage of electronics in automobiles grows, high-density packaging holding multiple die becomes increasingly important. With multi-die packaging, each of the die in the package must be highly reliable, enabling the multi-die package to meet the stringent reliability demands of the automotive manufacturers. Aehr Test’s FOX system provides full wafer contact parallel test and burn-in solutions for the die before they are assembled into the package. This enables the reliability screening to be done on the die before the assembly of the multi-die package, avoiding the costly scrapping of entire multi-chip packages when only one of the die fails the reliability screen.

About Micronas

Micronas (SIX Swiss Exchange: MASN), a semiconductor designer and manufacturer with worldwide operations, is a leading supplier of cutting-edge IC and sensor system solutions for automotive electronics. Micronas offers a variety of microcontrollers and Hall sensors for automotive and industrial applications, such as car dashboard, body control, as well as motor management and comfort functions. For more information on Micronas and its products, please visit www.micronas.com.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing memory and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the ABTS™, FOX, MTX and MAX systems and the DiePak® carrier. The ABTS system is Aehr Test's newest system for packaged part test during burn-in for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the ABTS technology, acceptance by customers of the ABTS systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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